

Hi-P Electronics Pte. Ltd. / H375iS

Page: 1 of 35

EMC Test Report

Project Number: 3986695

Report Number: 3986695EMC06 Revision Level: 0

Client: Hi-P Electronics Pte. Ltd.

Equipment Under Test: iDEN Cellular Phone with Bluetooth

Model: H375iS

FCC ID: 2ACUZ375iS

Applicable Standards: FCC Part 15 Subpart C, § 15.247

ANSI C63.10: 2013

Report issued on: 15 July 2016

Test Result: Compliant

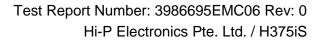
Tested by:	Mica
	Fabian Nica, Senior Technician
Reviewed by:	Anny O.S.
	Jeremy Pickens, Senior EMC Engineer

~/·

Remarks:

This report details the results of the testing carried out on one sample, the results contained in this test report do not relate to other samples of the same product. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

This report may only be reproduced and distributed in full. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or Testing done by SGS International Electrical Approvals in connection with distribution or use of the product described in this report must be approved by SGS international Electrical Approvals in writing.







1	SUN	MMARY OF TEST RESULTS	4
	1.1	MODIFICATIONS REQUIRED FOR COMPLIANCE	4
2	GE	NERAL INFORMATION	5
	2.1	CLIENT INFORMATION	5
	2.2	TEST LABORATORY	
	2.3	GENERAL INFORMATION OF EUT	
	2.4	EUT CONNECTION BLOCK DIAGRAM (CONDUCTED)	
	2.5	System Configurations	6
3	OC	CUPIED BANDWIDTH	7
	3.1	TEST RESULT	7
	3.2	TEST METHOD	
	3.3	TEST SITE	
	3.4	TEST EQUIPMENT	
	3.5	TEST DATA	7
4	PEA	AK OUTPUT POWER	11
	4.1	TEST RESULT	11
	4.2	TEST METHOD.	
	4.3	TEST SITE	11
	4.4	TEST EQUIPMENT	11
	4.5	TEST DATA	11
5	CO	NDUCTED SPURIOUS EMISSIONS AND BAND EDGE MEASUREMENTS	14
	5.1	TEST RESULT	14
	5.2	TEST METHOD	14
	5.3	TEST SITE	14
	5.4	TEST EQUIPMENT	
	5.5	TEST DATA (SPURIOUS EMISSIONS)	
	5.6	TEST DATA (BAND EDGES)	16
6	FIE	LD STRENGTH OF SPURIOUS RADIATION	18
	6.1	TEST RESULT	
	6.2	TEST METHOD	
	6.3	TEST SITE	
	6.4	TEST EQUIPMENT	
	6.5	TEST DATA (SPURIOUS EMISSIONS)	
	6.6	TEST DATA (BAND EGES)	
7	PSE	CUDO-RANDOM HOP SEQUENCE	
	7.1	TEST RESULT	
	7.2	TEST METHOD	
8	CH	ANNEL SEPARATION	30
	8.1	TEST RESULT	30
	8.2	TEST METHOD	30
	8.3	TEST SITE	30
	8.4	TEST EQUIPMENT	
	8.5	TEST DATA	31
9	NU	MBER OF HOPPING CHANNELS	32
	9.1	TEST RESULT	32
	9.2	TEST METHOD.	32
	9.3	Test Site 32	
	SGS North	America Inc. Consumer Testing Services 620 Old Peachtree Road NW, Suite 100, Suwanee, GA 30024 t (770) 570-1800 www.us.sgs.com/cts	



Page: 3 of 35

9.4	TEST EQUIPMENT	32
9.5	TEST DATA	33
10 DW	VELL TIME	34
	TEST RESULT	
	TEST METHOD.	
10.3	TEST SITE	34
10.4		
10.5	TEST DATA	34
11 RE	VISION HISTORY	35



Hi-P Electronics Pte. Ltd. / H375iS

Page: 4 of 35

Summary of Test Results

Test Description	Test Specification	Test Result
Occupied Bandwidth	15.247(a) (1)	Compliant
Peak Power Output	15.247(a) (1)	Compliant
Conducted Spurious Emissions	15.247(d)	Compliant
Band Edge	15.247(d)	Compliant
Radiated Spurious Emissions	15.247(d), 15.35(b),15.209	Compliant
Dwell time	15.247(a) (1)(iii)	Compliant
Number of Hopping Frequencies	15.247(a) (1)(iii)	Compliant
Channel separation	15.247(a) (1)(iii)	Compliant

Modifications Required for Compliance

None



Hi-P Electronics Pte. Ltd. / H375iS

Page: 5 of 35

General Information

Client Information 2.1

Name: Hi-P Electronics Pte. Ltd.

Address: 12 ANG MO KIO STREET 64 #03-02, UE BIZHUB CENTRAL (BLK A)

City, State, Zip, Country: SINGAPORE

569088

Test Laboratory 2.2

Name: SGS North America, Inc.

Address: 620 Old Peachtree Road NW, Suite 100

City, State, Zip, Country: Suwanee, GA 30024, USA

General Information of EUT 2.3

Marketing Name: iDEN Cellular Phone with Bluetooth

Model Number: H375iS

364KSL01GQ (Radiated Measurements) Serial Number: 364KRE009J (Conducted Measurements)

Frequency Range: 2402 to 2480 MHz

Number of channels: 79

Modulation type: GFSK, DQPSK, 8DPSK

Channel spacing: 1 MHz

Antenna: Integral

Rated Voltage: 3.7 VDC Internal Battery

Sample Received Date: 24 June 2016 (radiated sample)

22 April 2015 (conducted sample)

Dates of testing: 28 April – 13 May 2015 (Conducted Measurements)

10 – 11 July, 2016

Note: Conducted measurements were taken on a model H375i certified under FCC ID: 2ACUZ H375I. The Bluetooth chipset and power configurations are identical to the previous evaluation, and therefore, the conducted results are unchanged. Only radiated spurious and radiated band edge measurements were performed on the mode H375iS to cover the new phone configuration.

Operating Modes and Conditions

The EUT was configured in software to allow the user to the control the EUT to run continuously exercising all modes of operation.

During testing, the hopping sequence was stopped in accordance with Section 5.1 of ANSI C63.10:2013 so that the low, mid and high channels could be tested independently.

Modulations used: For fundamental and spurious measurements, the EUT was configured to operate continuously with Bluetooth modulation enabled.

As specified in Section 5.10.5 of ANSI C63.10:2013:

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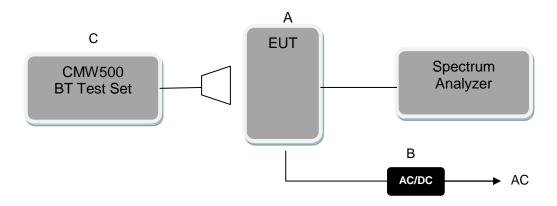


Hi-P Electronics Pte. Ltd. / H375iS

Page: 6 of 35

- Software was designed to allow the EUT to operate
 - o at 100 % duty cycle
 - at the worst-case duty cycle to allow measurements in instances where an average correction factor needs to be determined to calculate the average field strength from the measured peak field strength
- The software allowed configuration and operation on all available unlicensed wireless device channels.
- The software allowed configuration and operation using all available modulations and data rates
- The software allowed configuration and operation on all available power out levels
- Since this is a frequency hopping system, the software allowed the hopping sequence to be turned off

EUT Connection Block Diagram (Conducted)



System Configurations 2.5

Device reference	Manufacturer	Description	Model Number	Serial Number
А	Hi-P Technology	iDEN Cellular Phone with Bluetooth	H375iS	Radiated: 364KSL01GQ Conducted: 364KRE009J
В	Phihong	Switching Power Supply	PSB05R-050Q	Not Labeled
С	R&S	Communications Analyzer	CMW500	100232



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Page: 7 of 35

Occupied Bandwidth

Test Result 3.1

Test Description	Basic Standards	Test Result
20 dB bandwidth	15.247(a)(1)	Pass

Test Method 3.2

The procedures from ANSI C63.10 Clause 6.9.2 were used to determine the 20 dB bandwidth.

Test Site 3.3

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 22.7 °C Relative Humidity: 36.9 %

Test Equipment 3.4

Test Date: 28 April 2015

Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU40	R&S	B079629	28 JUL 2015
RF Cable	Sucoflex 102	Huber-Suhner	B079823	06 AUG 2015

Note: The equipment calibration period is 1 year.

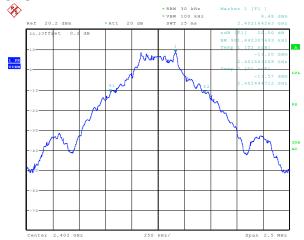
Test Data 3.5

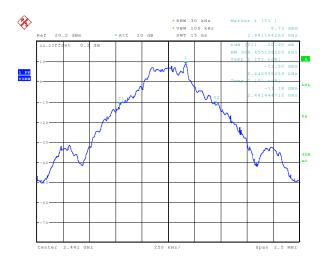
Frequency	Channel No	Modulation	20 dB bandwidth kHz
		GFSK	901
2402	0	EDR-2	1298
		EDR-3	1338
	39	GFSK	909
2441		EDR-2	1346
		EDR-3	1334
		GFSK	953
2480	78	EDR-2	1342
		EDR-3	1334



Page: 8 of 35

GFSK





Date: 28.APR.2015 05:40:52



Date: 28.APR.2015 05:46:38

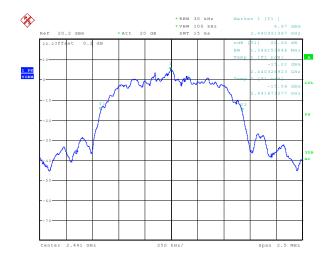
Date: 28.APR.2015 05:52:43



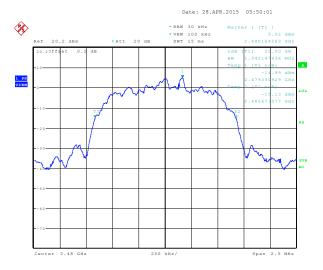
Page: 9 of 35

EDR 2





Date: 28.APR.2015 05:42:16



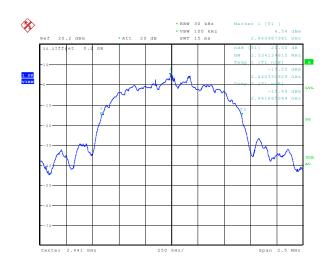
Date: 28.APR.2015 05:53:41



Page: 10 of 35

EDR-3





Date: 28.APR.2015 05:43:14



Date: 28.APR.2015 05:50:42

Date: 28.APR.2015 05:54:32



Hi-P Electronics Pte. Ltd. / H375iS

Page: 11 of 35

Peak Output Power

Test Result

Test Description	Test Specification	Test Result
Peak Output Power	15.247(a) (1)	Compliant

Test Method

Measurements were recorded using the test methods defined in ANS C63.10, Clause 7.8.5.

Limit

For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 hopping channels: 1 watt.

Test Site 4.3

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 22.7 °C Relative Humidity: 36.9 %

Test Equipment

Test Date: 28 April 2015

Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU40	R&S	B079629	28 JUL 2015
RF Cable	Sucoflex 102	Huber-Suhner	B079823	06 AUG 2015

Note: The equipment calibration period is 1 year.

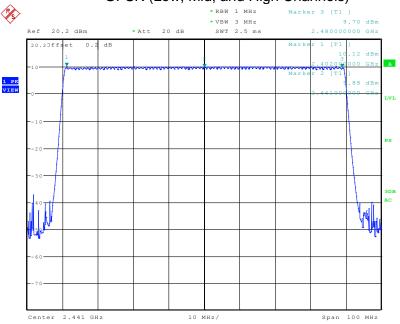
Test Data 4.5

Frequency	Channel No	Modulation	Peak Output Power (dBm)	Peak Output Power (W)
		GFSK	10.1	0.010
2402	0	EDR-2	9.1	0.008
		EDR-3	9.3	0.008
		GFSK	9.9	0.010
2441	39	EDR-2	9.4	0.009
		EDR-3	9.8	0.010
		GFSK	9.7	0.009
2480	78	EDR-2	9.3	0.008
		EDR-3	9.6	0.009

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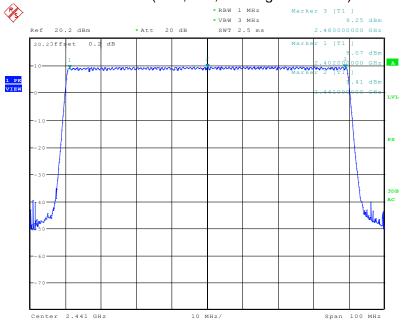
Page: 12 of 35

GFSK (Low, Mid, and High Channels)



Date: 28.APR.2015 03:30:03

EDR2 (Low, Mid, and High Channels)

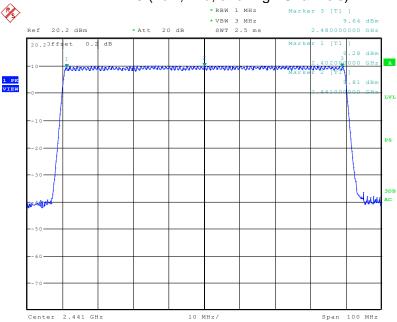


Date: 28.APR.2015 05:30:06

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Page: 13 of 35

EDR3 (Low, Mid, and High Channels)



Date: 28.APR.2015 05:31:58



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Page: 14 of 35

Conducted Spurious Emissions and Band Edge Measurements

Test Result 5.1

Test Description	Test Specification	Test Result
Conducted Spurious Emissions	15.247(d)	Compliant

Test Method

Measurements were recorded using the test methods defined in ANS C63.10, Clause 7.8.8.

The limit is 20 dB below the measured peak power.

Test Site 5.3

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 22.7 °C Relative Humidity: 37.1 %

Test Equipment

Test Date: 28 April 2015

Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU40	R&S	B079629	28 JUL 2015
RF Cable	Sucoflex 102	Huber-Suhner	B079823	06 AUG 2015

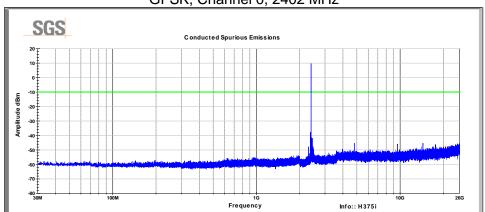
Note: The equipment calibration period is 1 year.



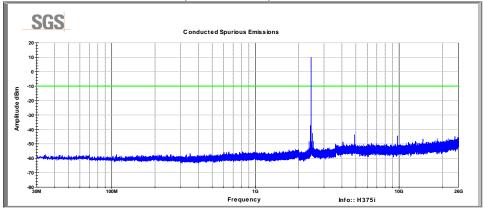
Test Data (Spurious Emissions) 5.5

No spurious emissions detected within 20dB of the limit.

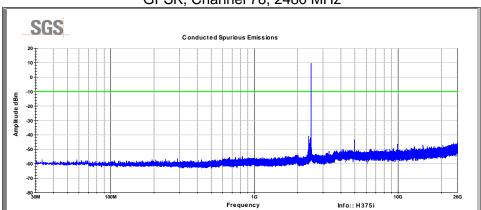
GFSK, Channel 0, 2402 MHz



GFSK, Channel 39, 2441 MHz



GFSK, Channel 78, 2480 MHz



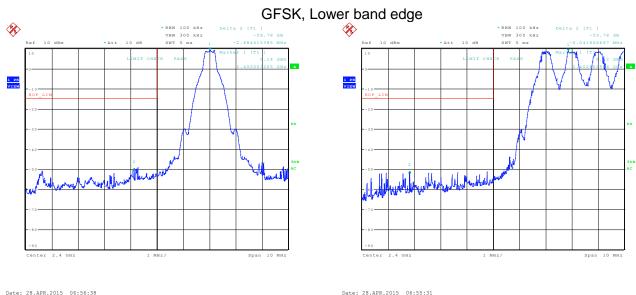


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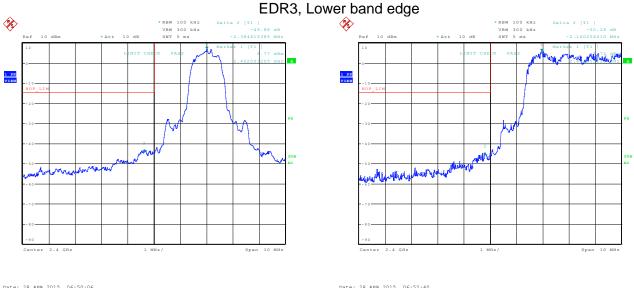
Page: 16 of 35

Test Data (Band Edges) 5.6

There were no emissions within 20 dB of the limit. Tests performed in hopping and non-hopping modes.



Date: 28.APR.2015 06:55:31



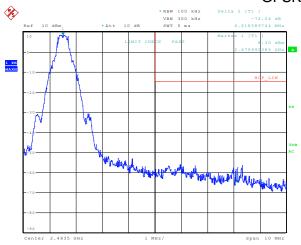
Date: 28.APR.2015 06:50:06 Date: 28.APR.2015 06:52:40

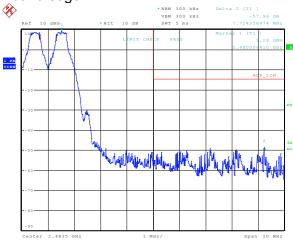


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Page: 17 of 35

GFSK, Upper band edge

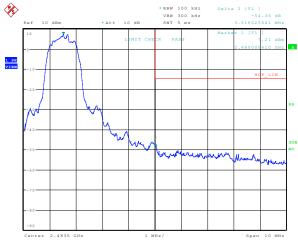


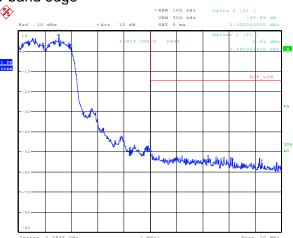


Date: 28.APR.2015 06:59:10

Date: 28.APR.2015 07:01:22

EDR3, Upper band edge





Date: 28.APR.2015 07:03:35

Date: 28.APR.2015 07:06:09



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Page: 18 of 35

Field Strength of Spurious Radiation

Test Result 6.1

Test Description	Test Specification	Test Result
Field strength of spurious radiation	15.247(d), 15.35(b),15.205, 15.209	Compliant

Test Method 6.2

Radiated spurious emissions measurements were recorded with the device configured to transmit at the lowest, middle, and highest channels. The frequency range investigated was up through the 10th harmonic of the fundamental transmit frequency. The methods defined in ANSI C63.10: 2013 were used.

For measurements below 1GHz, the device was placed in hopping mode and manipulated through three orthogonal axes.

Above 1GHz, the device was tested with the transmit frequency fixed at low, middle, and high channels and the alternative method defined in ANSI C63.10 Clause 6.6.5 was used.

Test distance:

30 MHz to 1 GHz - The EUT to measurement antenna distance is 3 meters 1 to 18 GHz - The EUT to measurement antenna distance is 3 meters 18 to 40 GHz - The EUT to measurement antenna distance is 1 meter

Гиолиопои	Lin	Peak Limits	
Frequency	Microvolts/m	dBuV/m	dBuV/m
30 - 88 MHz	100	40 ⁽²⁾	
88 - 216 MHz	150	43.5 (2)	
216 - 960 MHz	200	46 ⁽²⁾	
960 - 1000 MHz	500	54 ⁽²⁾	
1 - 40 GHz	500	54 ⁽³⁾	74

⁽¹⁾ These limits are applicable to emissions within the restricted bands of operation defined in FCC §15.205.

- (2) Quasi-peak limit
- (3) Average limit



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Page: 19 of 35

Test Site

3m Absorber Lined Shielded Enclosure (ALSE), Suwanee, GA

Environmental Conditions

Temperature: 23.8 °C Relative Humidity: 46.6 %

Test Equipment 6.4

Test End Date: 11-Jul-2016 Tester: JOP

Test Ella Bate. 11 da 2010		103001. 301		
Equipment	Model	Manufacturer	Asset Number	Cal Due Date
EMI TEST RECEIVER	ESU40	ROHDE & SCHWARZ	B079629	4-Aug-2016
ANTENNA, BILOG	JB6	SUNOL	B079690	21-Oct-2016
DRG HORN (MEDIUM)	3117	ETS-LINDGREN	B079699	26-Apr-2017
PREAMPLIFIER	TS-PR18	ROHDE & SCHWARZ	B094463	16-Feb-2017
RF CABLE	NMS-290-236.2-NMS	FLORIDA RF LABS	B095020	4-Aug-2016
RF CABLE	NFS-290-78.7-NFS	FLORIDA RF LABS	B095019	4-Aug-2016
RF CABLE - 7500MM (10KHZ - 18GHZ)	SF106	HUBER&SUHNER	B079713	3-Aug-2016
RF CABLE - 7000MM (10KHZ - 18GHZ)	SF106	HUBER&SUHNER	B079716	3-Aug-2016
COAXIAL CABLE	SUCOFLEX 100	HUBER&SUHNER	B108523	27-Oct-2016
RF CABLE	SF106	HUBER&SUHNER	B085892	3-Aug-2016
COAXIAL CABLE	1134	GORE	B094785	4-Aug-2016
WIDEBAND RADIO	CMW500	ROHDE & SCHWARZ	B079788	21-Oct-2017
COAXIAL CABLE	SUCOFLEX 102	HUBER&SUHNER	B079822	4-Aug-2016
COAXIAL CABLE	SUCOFLEX 102	HUBER&SUHNER	B079824	4-Aug-2016
FIXED GAIN AMPLIFIER	NSP1840-HG	MITEQ	B087572	15-Oct-2016
DRG HORN (SMALL)	3116B	ETS-LINDGREN	B079697	29-Mar-2017

Note: The equipment calibration period is 1 year.

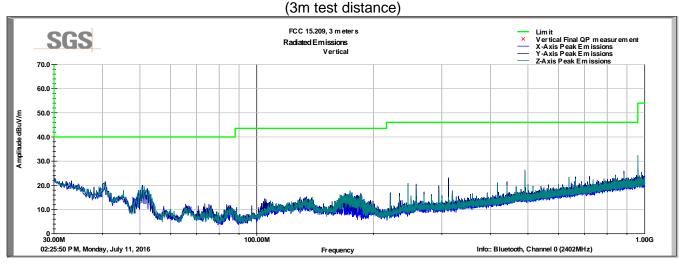


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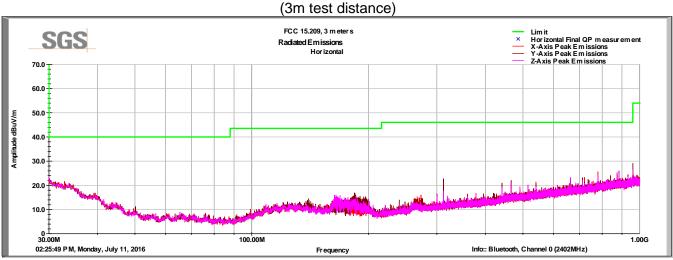
Page: 20 of 35

Test Data (Spurious Emissions)

Bluetooth, Hopping on all 79 Channels 30-1000MHz Vertical



Bluetooth, Hopping on all 79 Channels 30-1000MHz Horizontal

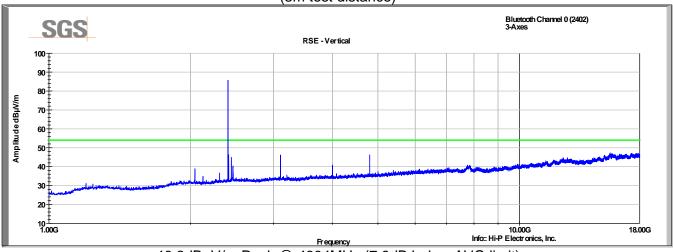




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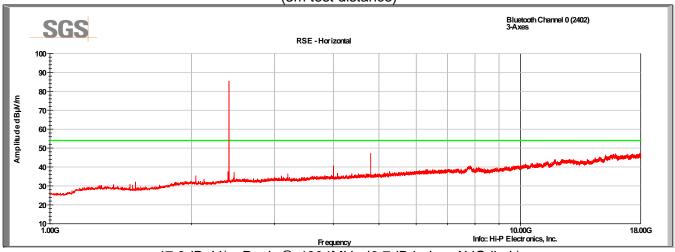
Page: 21 of 35

Bluetooth, Channel 0 1-18GHz Vertical (3m test distance)



46.2dBµV/m Peak @ 4804MHz (7.8dB below AVG limit)

Bluetooth, Channel 0 1-3GHz Horizontal (3m test distance)



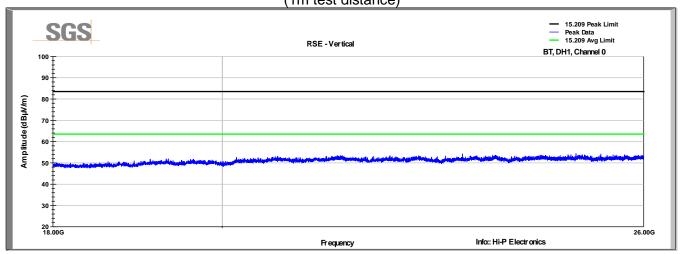
47.3dBµV/m Peak @ 4804MHz (6.7dB below AVG limit)



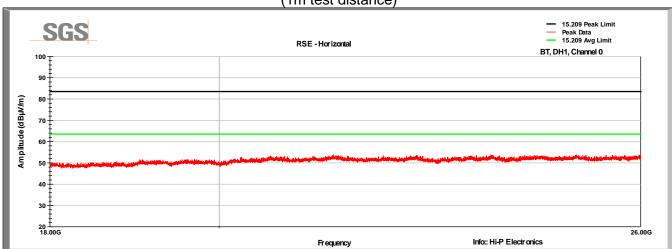
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Page: 22 of 35

Bluetooth, Channel 0 18-26GHz Vertical (1m test distance)



Bluetooth, Channel 0 18-26GHz Horizontal (1m test distance)

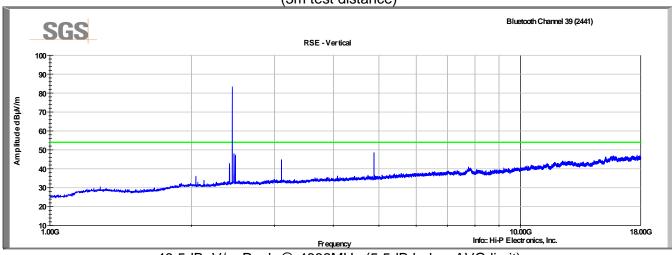




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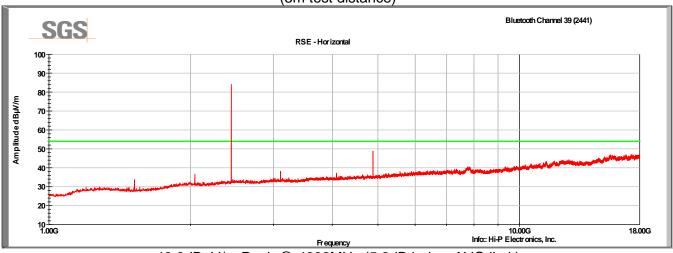
Page: 23 of 35

Bluetooth, Channel 39 1-18GHz Vertical (3m test distance)



48.5dBµV/m Peak @ 4882MHz (5.5dB below AVG limit)

Bluetooth, Channel 39 1-18GHz Horizontal (3m test distance)



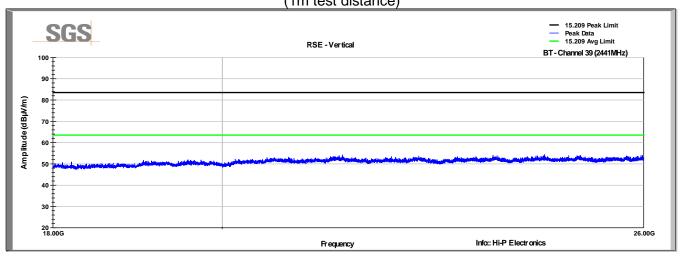
48.8dBµV/m Peak @ 4882MHz (5.2dB below AVG limit)



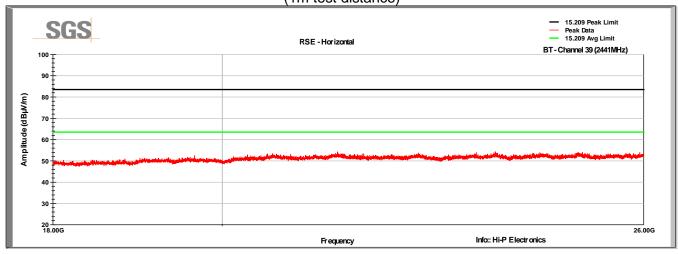
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Page: 24 of 35

Bluetooth, Channel 39 18-26GHz Vertical (1m test distance)



Bluetooth, Channel 39 18-26GHz Horizontal (1m test distance)

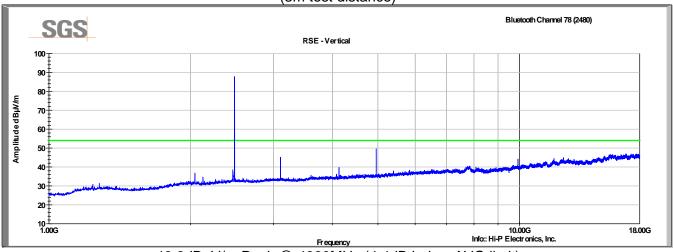




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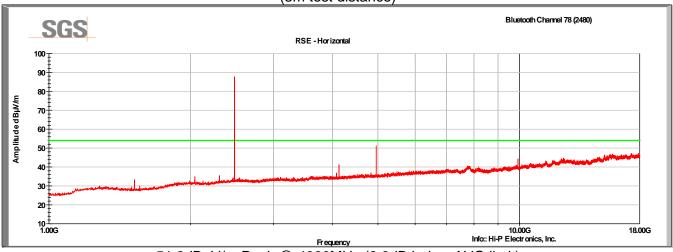
Page: 25 of 35

Bluetooth, Channel 78 1-18GHz Vertical (3m test distance)



49.6dBµV/m Peak @ 4960MHz (4.4dB below AVG limit)

Bluetooth, Channel 78 1-18GHz Horizontal (3m test distance)



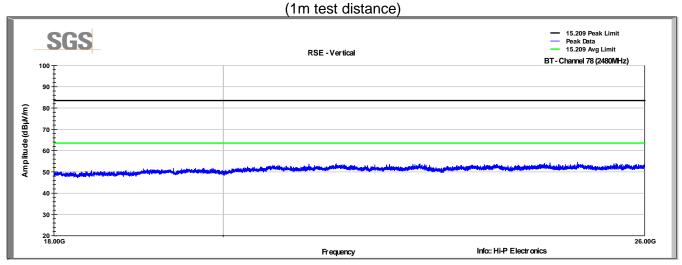
51.2dBµV/m Peak @ 4960MHz (2.8dB below AVG limit)



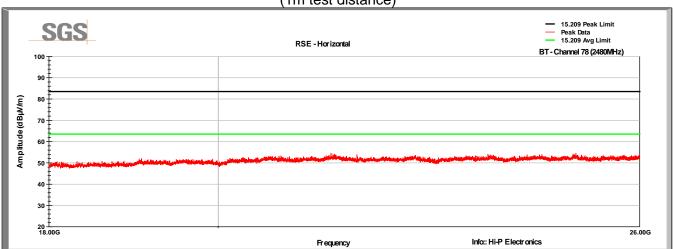
Hi-P Electronics Pte. Ltd. / H375iS

Page: 26 of 35

Bluetooth, Channel 78 18-26GHz Vertical



Bluetooth, Channel 78 18-26GHz Horizontal (1m test distance)

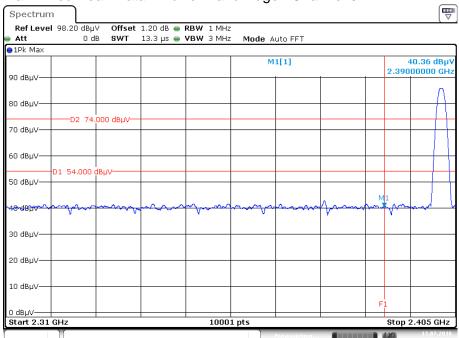


Hi-P Electronics Pte. Ltd. / H375iS

Page: 27 of 35

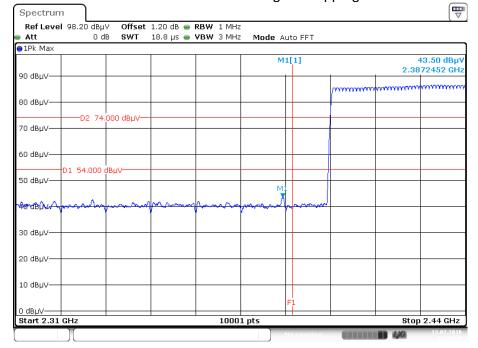
Test Data (Band Eges)

Maximized Peak Data - Lower Band Edge- Channel 0



Date: 13.JUL.2016 09:31:34

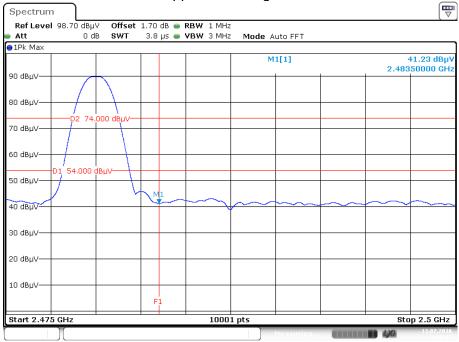
Maximized Peak Data - Lower Band Edge - Hopping



Date: 13.JUL.2016 09:39:40

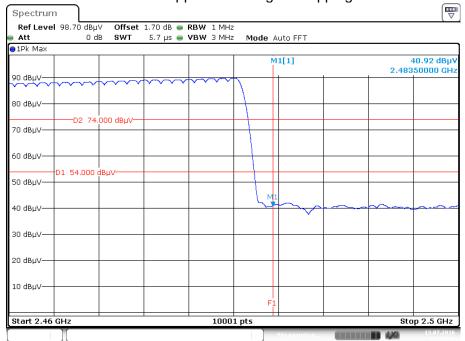
Hi-P Electronics Pte. Ltd. / H375iS Page: 28 of 35

Maximized Peak Data - Upper Band Edge- Channel 78



Date: 13.JUL.2016 11:28:15

Maximized Peak Data - Upper Band Edge - Hopping



Date: 13.JUL.2016 11:30:46



Hi-P Electronics Pte. Ltd. / H375iS

Page: 29 of 35

Pseudo-Random Hop Sequence

Test Result 7.1

Test Description	Test Specification	Test Result
Pseudo-Random Hop Sequence	15.247(d)	Compliant ⁽¹⁾

Note (1): The theory of operation states that the device is Bluetooth and operates using a pseudorandom hopping technique.

7.2 Test Method

Compliance is demonstrated by Manufacturer's declaration or is stated in the Theory of Operation.

Requirement

The hopset shall be such that the near-term distribution of frequencies appears random, with sequential hops randomly distributed in both direction and magnitude of change in the hopset, while the long-term distribution appears evenly distributed.



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Page: 30 of 35

Channel Separation

Test Result 8.1

Test Description	Test Specification	Test Result
Number of Hopping Channels	15.247(a)(1)	Compliant

Test Method 8.2

The test data was measured using a spectrum analyzer with Peak detector (max hold) and a resolution bandwidth of 100 kHz. The trace was allowed to stabilize until all channels were displayed.

Requirement

Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the -20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the band 2400-2483.5 MHz may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the -20 dB bandwidth of the hopping channel, whichever is greater, provided that the systems operate with an output power no greater than 0.125 W.

Test Site 8.3

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 22.9 °C Relative Humidity: 49.4 %

Test Equipment

Test Date: 12 May 2015

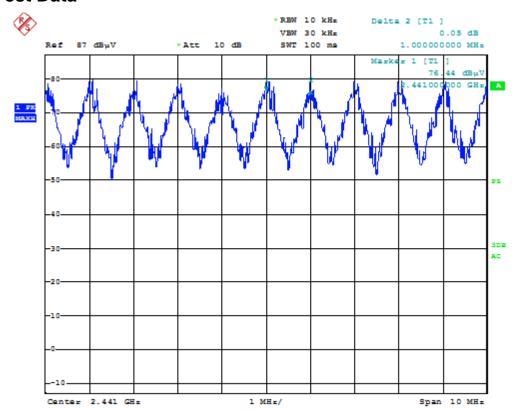
Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU08	R&S	B085759	26 JUN 2015
Coaxial Cable	141	Huber-Suhner	B095589	06 AUG 2015

Note: The equipment calibration period is 1 year.

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Page: 31 of 35

Test Data 8.5



Date: 12.MAY.2015 08:29:36



Hi-P Electronics Pte. Ltd. / H375iS

Page: 32 of 35

Number of Hopping Channels

Test Result 9.1

Test Description	Test Specification	Test Result
Number of Hopping Channels	15.247(a)(1)(i)	Compliant

Test Method 9.2

The test data was measured using a spectrum analyzer with Peak detector (max hold) and a resolution bandwidth of 30 kHz. The trace was allowed to stabilize until all channels were displayed.

Requirement

Frequency hopping systems operating in the band 2400-2483.5 MHz shall use at least 15 hopping channels.

Test Site 9.3

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 23.1 °C Relative Humidity: 43.9 %

Test Equipment 9.4

Test Date: 12 May 2015

Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU08	R&S	B085759	26 JUN 2015
Coaxial Cable	141	Huber-Suhner	B095589	06 AUG 2015

Note: The equipment calibration period is 1 year.

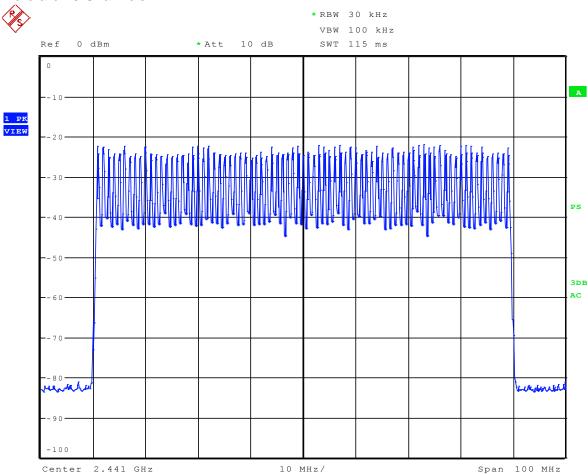


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Page: 33 of 35

Test Data 9.5

There are 79 Channels.



Date: 12.MAY.2015 09:16:27

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Page: 34 of 35

10 Dwell Time

10.1 Test Result

Test Description	Test Specification	Test Result
Dwell Time	15.247(a)(1)(i)	Compliant

10.2 Test Method

Bluetooth BR/EDR mode has a channel hopping rate of 1600 hops/s. Since BR/EDR modes use 5 transmit and 1 receive slot, for a total of 6 slots, the Bluetooth transmitter is actually hopping at a rate of 1600 / 6 = 266.67 hops/s.

- 400ms x 79 hopping channels = 31.6 sec (Time of Occupancy Limit)
- Worst case BT has 266.67 hops/second (for BR/EDR modes with DH5 operation)
- 266.67 hops/second / 79 channels = 3.38 hops/second (# hops/second on one channel)
- 3.38 hops/second/channel * 31.6 seconds = 106.67 hops (# hops over a 31.6 second period)
- 106.67 hops x 2.9 ms/channel = 309.34 ms (worst case dwell time for one channel in BR/EDR modes)

Requirement

The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds, multiplied by the number of hopping channels employed.

10.3 Test Site

SGS EMC Laboratory, Suwanee, GA

Environmental Conditions

Temperature: 23.1 °C Relative Humidity: 43.9 %

10.4 Test Equipment

Test Date: 12 May 2015

Equipment	Model	Manufacturer	Asset Number	Cal Due Date
Receiver	ESU08	R&S	B085759	26 JUN 2015
Coaxial Cable	141	Huber-Suhner	B095589	06 AUG 2015

Note: The equipment calibration period is 1 year.

10.5 Test Data

	Packet Type	Pulse Width ms	Dwell Time Sec	Limit	Result
	DH1	0.399	0.13	0.4	PASS
BR	DH3	1.657	0.27	0.4	PASS
	DH5	2.907	0.31	0.4	PASS
EDR2	DH1	0.399	0.13	0.4	PASS
	DH3	1.657	0.27	0.4	PASS
	DH5	2.907	0.31	0.4	PASS
	DH1	0.399	0.13	0.4	PASS
EDR3	DH3	1.657	0.27	0.4	PASS
	DH5	2.907	0.31	0.4	PASS

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Page: 35 of 35

11 Revision History

Revision Level	Description of changes	Revision Date
0	Initial release	15 July 2016